

Vertex Detectors for Future Linear Colliders

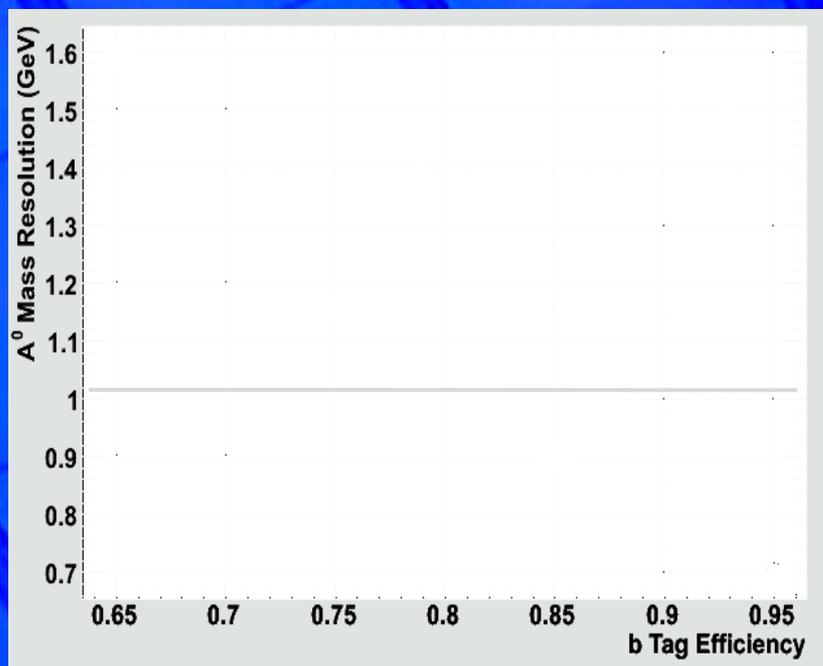
Marco Battaglia
UCSC, LBNL and CERN

with contributions from L Andricek, Y Arai, R Lipton,
N Sinev, W Snoeys, G Varner, S Zalusky

ALCPG2011

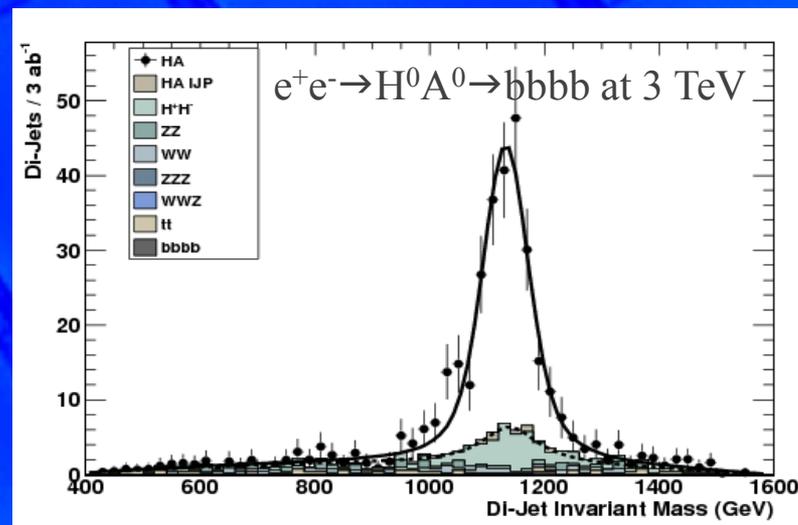
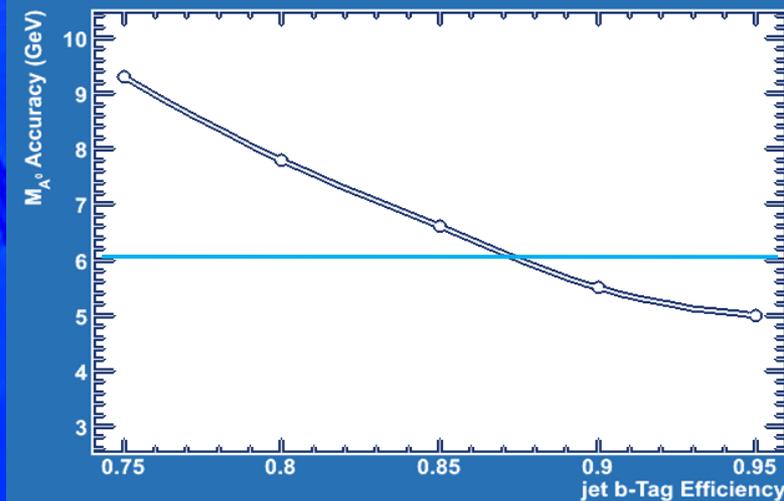
March 23, 2011 Oregon University, Eugene OR

Multi-b Final States and Jet flavour tagging



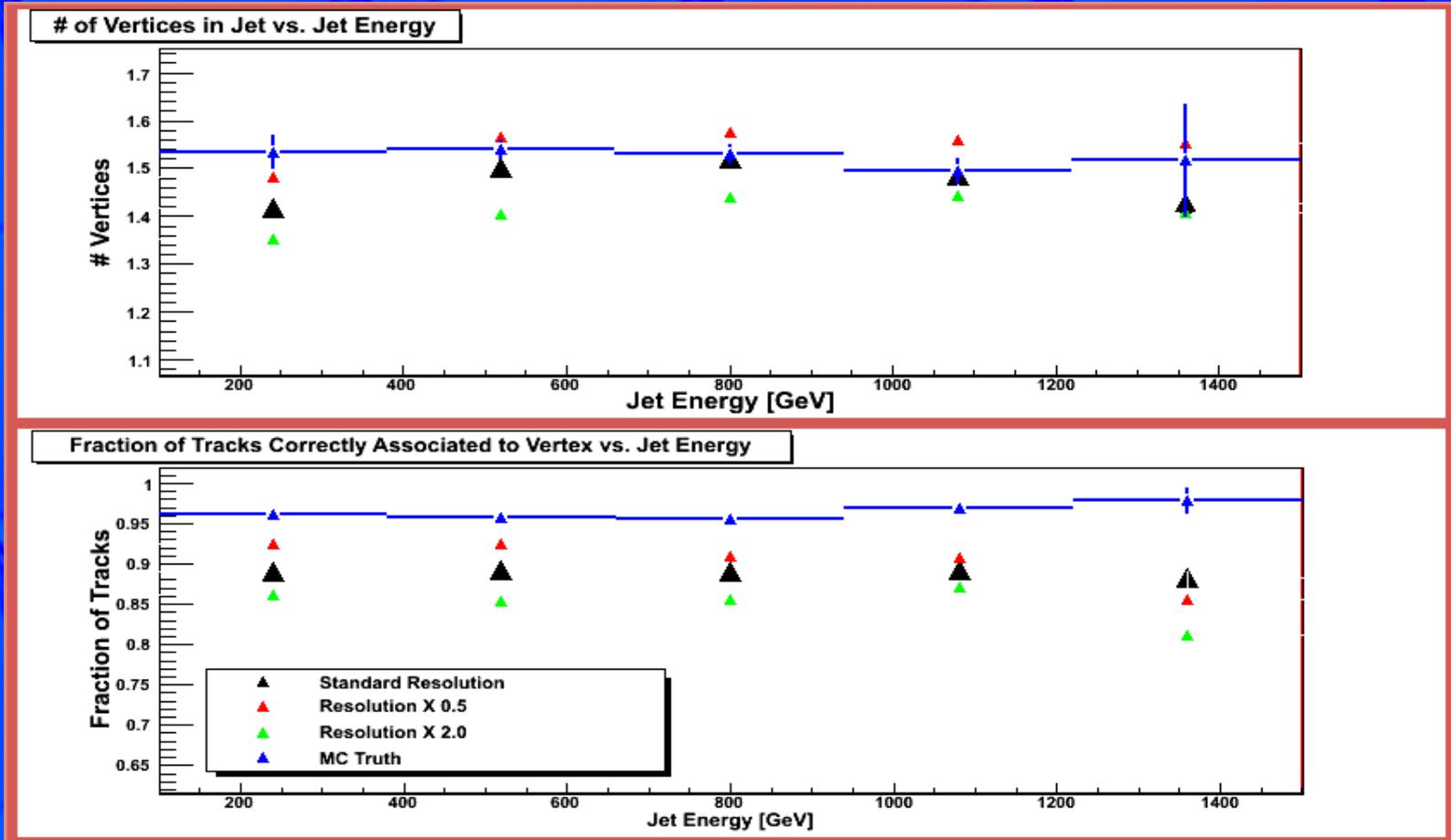
MB et al. PRD78 (2008)

σ_{IP} (μm)	b Purity	ϵ_b
$5 \oplus 10 / p_t$	0.9	0.75
$12 \oplus 70 / p_t$	0.9	0.25



Jet flavour tagging and Track Extrapolation Resolution

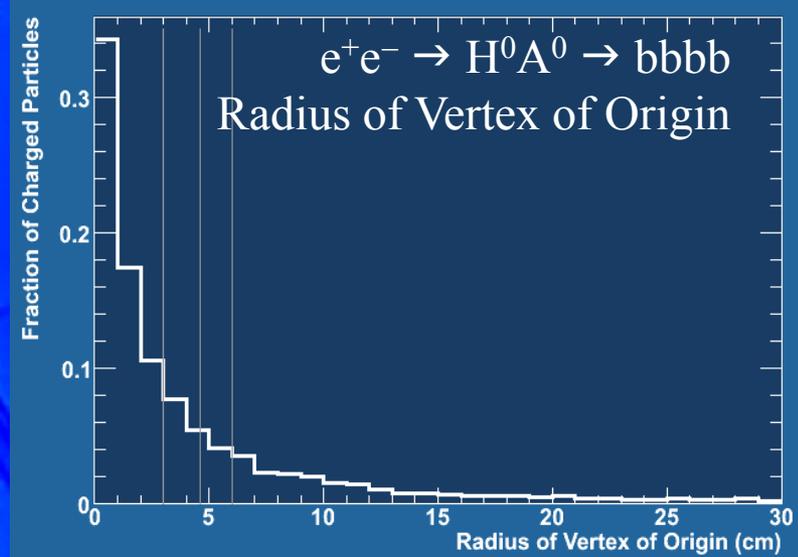
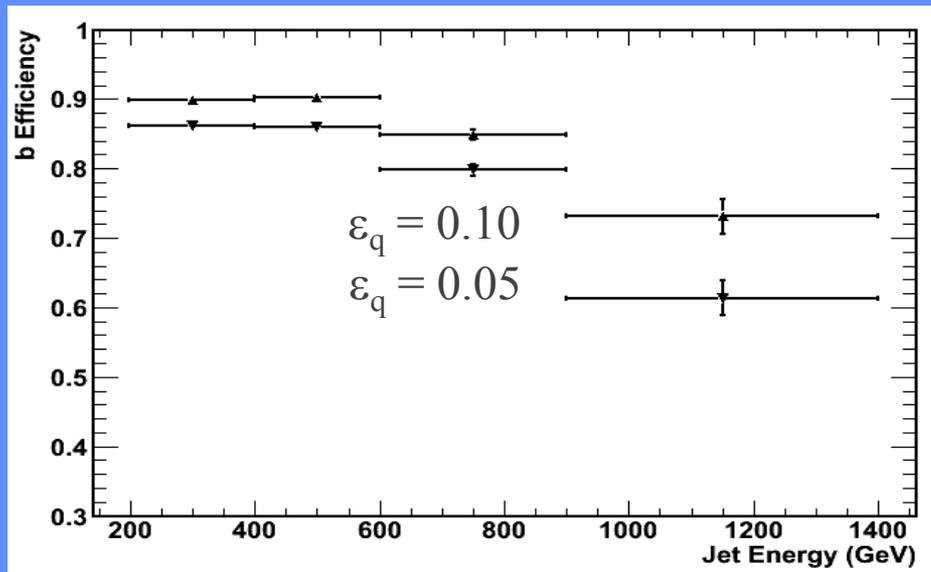
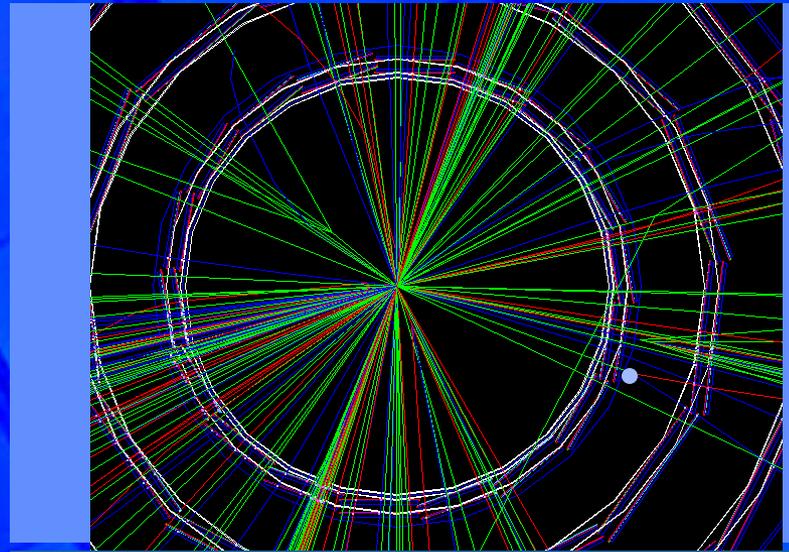
Performance of Jet Flavour Tagging at 3 TeV for std resolution $\sigma_{ip} = 3 \oplus 18 / p_t$
 $\sigma_{ip}/2$, $\sigma_{ip} \times 2$ and unsmeared track parameters vs. E_{jet}



Jet flavour tagging and Track Extrapolation Resolution

Issues at large jet energies

Long B hadron decay distance past detector innermost layer(s) and reduced fraction of secondary particles in jet, limit performance of topological vertex search at TeV energies:

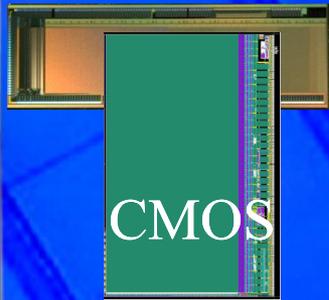


Linear Collider Pixel Sensor R&D

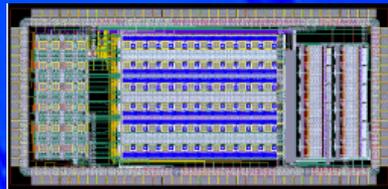


Requirements for the LC Vertex Tracker ($\sim 3 \mu\text{m}$ single point resolution, $\sim 0.1\% X_0$ per active layer, power dissipation $< 100 \text{ mW cm}^{-2}$, readout $\sim 50 \text{ MHz}$ [$+ \sim O(10\text{ns})$ time stamping at CLIC], $\sim 10\text{-}20 \mu\text{m}$ pixel pitch) require new generation of Si pixels:

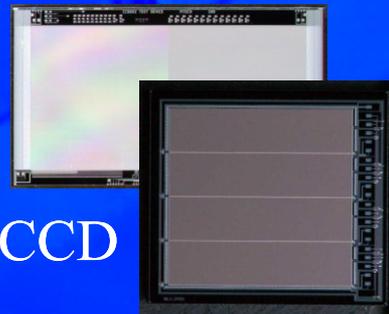
Monolithic Si Pixel Technologies



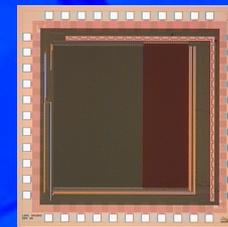
CMOS



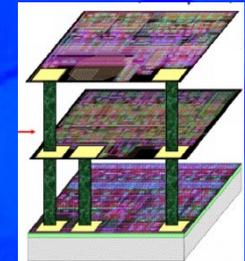
DEPFET



CCD



SOI

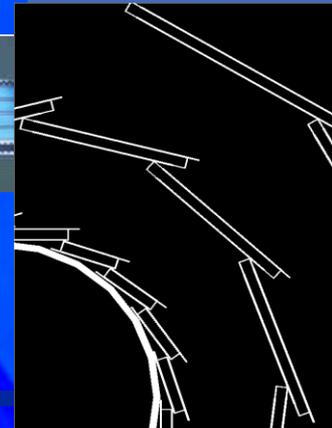


3D

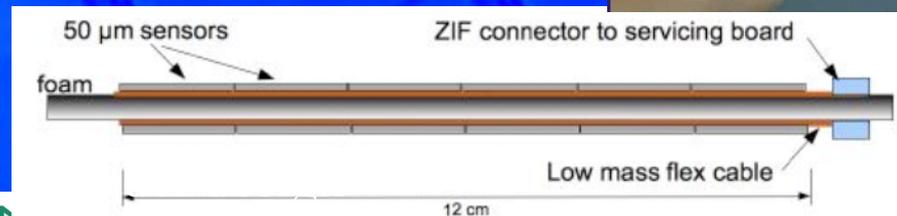
Vertical Integration

Architectures with advanced in-pixel and on-chip data processing

Innovative light-weight Ladders and Cooling



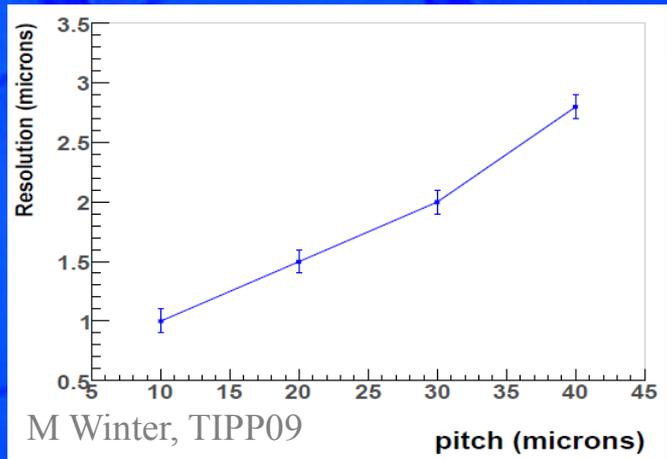
Thin sensors



Single Point Resolution

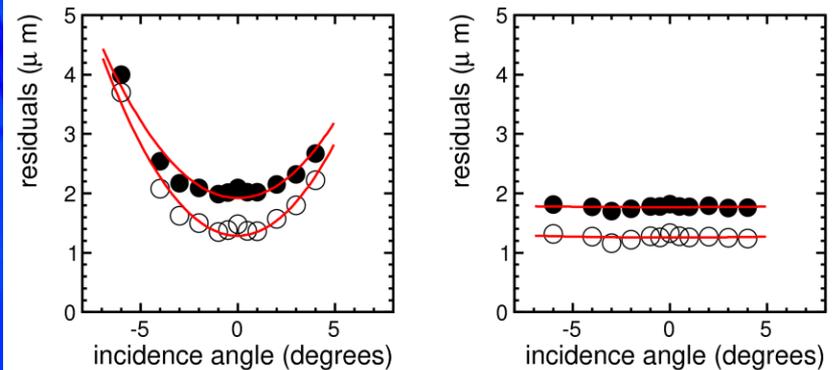


σ_{point} vs pitch

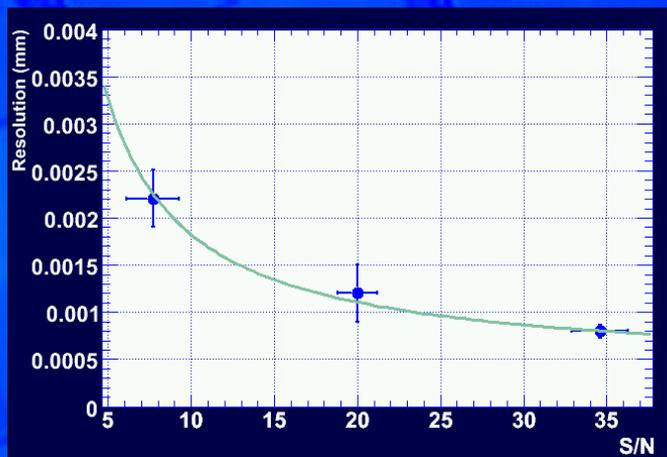


σ_{point} vs incidence angle

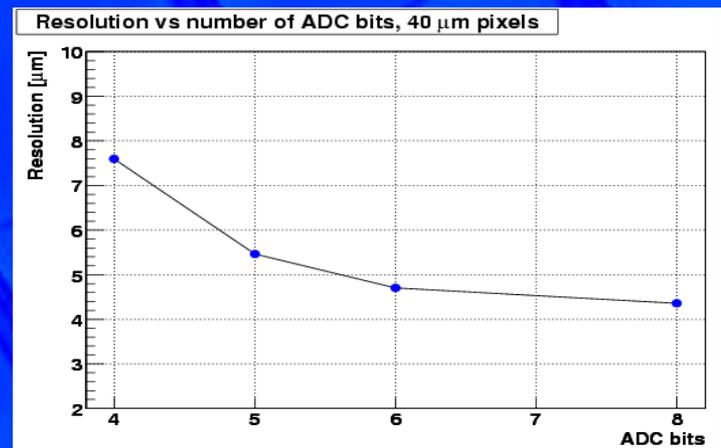
DEPFET TB2008, 120 GeV pions, $90^\circ \pm 5^\circ$, $24 \times 24 \mu\text{m}^2$ pixel



σ_{point} vs S/N



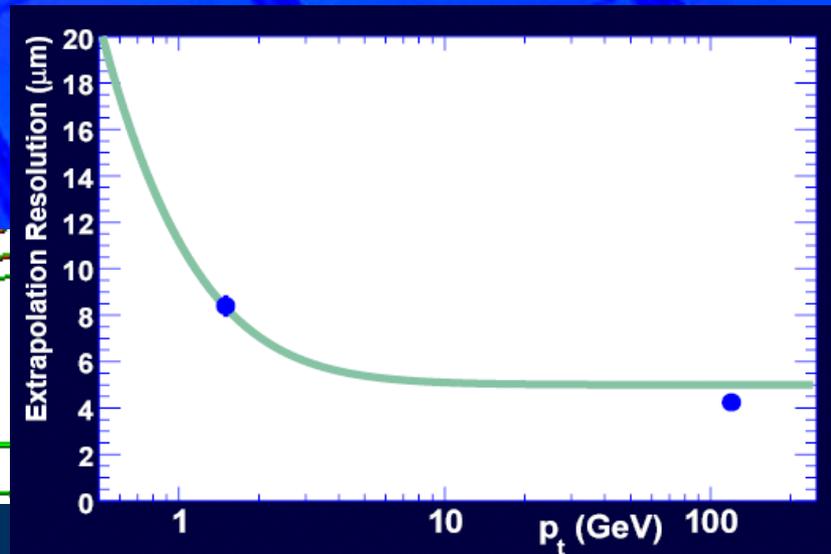
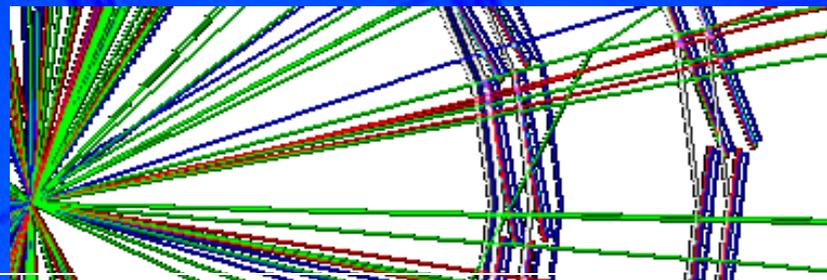
σ_{point} vs ADC accuracy



Track Extrapolation and Vertexing resolution



ILC/CLIC target track extrapolation accuracy demonstrate with small beam telescopes based on thin pixels:

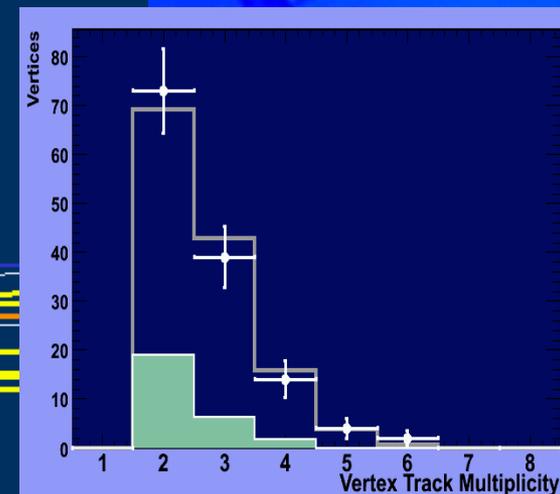


FNAL MBTF T966 Data
120 GeV p on Cu target
LBNL Thin CMOS Pixel Telescope

Extrapolate 3 cm upstream from first Si pixel layer:

T966 σ_z vertex resolution = 230 μm

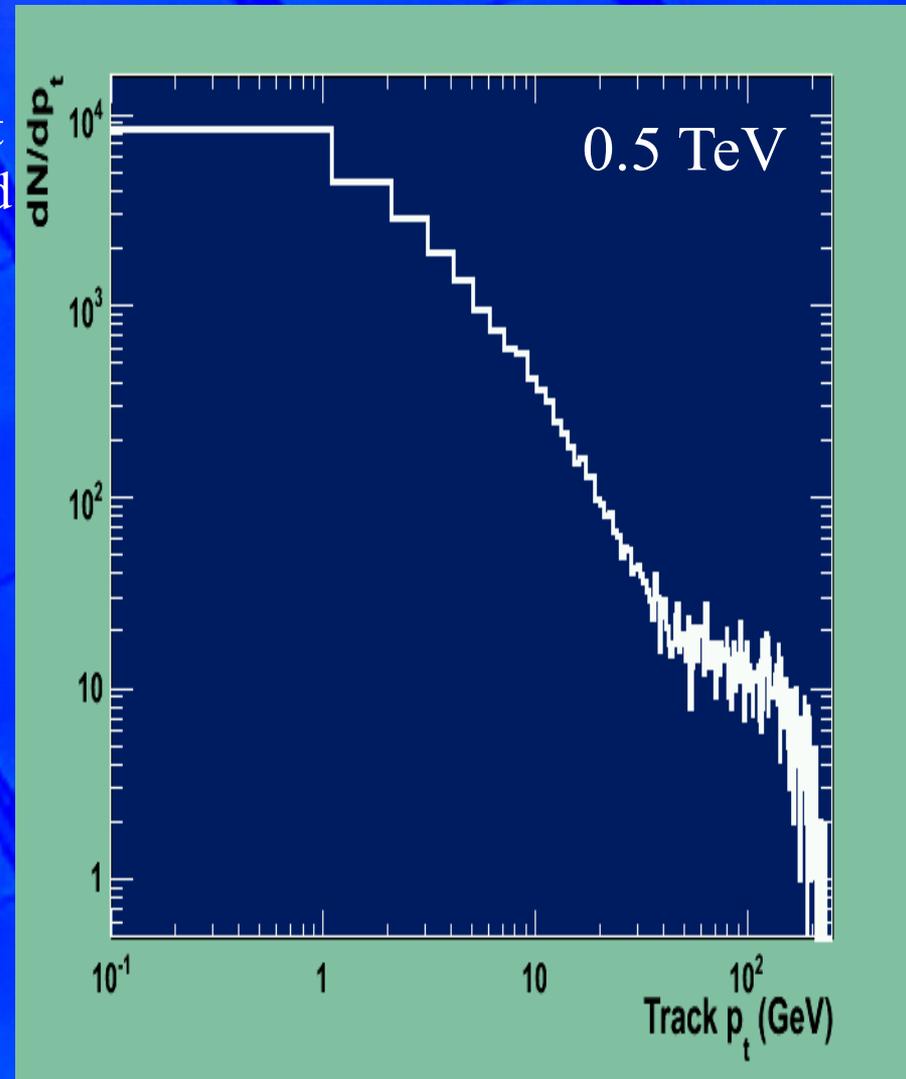
CLIC σ_z vertex resolution in B decays = 210 μm



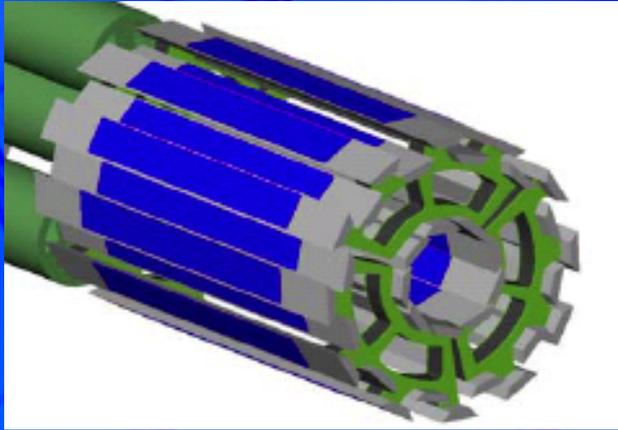
Despite large centre-of-mass energies, charged particles produced with moderate energies: interesting processes have large jet multiplicity (4 and 6 parton processes + hard gluon radiation) or large missing energies; Excellent track extrapolation at low momenta essential.

Impact Parameter resolution
 $a+b/p_t$ for ILC-like VTX
 with Si on 100 μm CFC

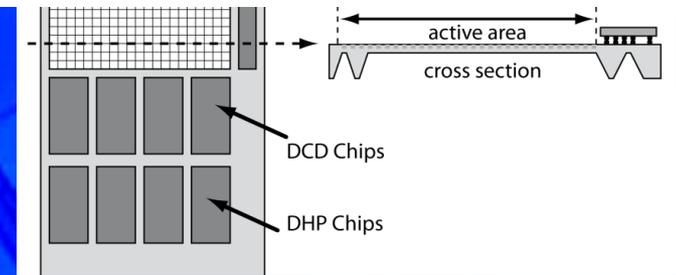
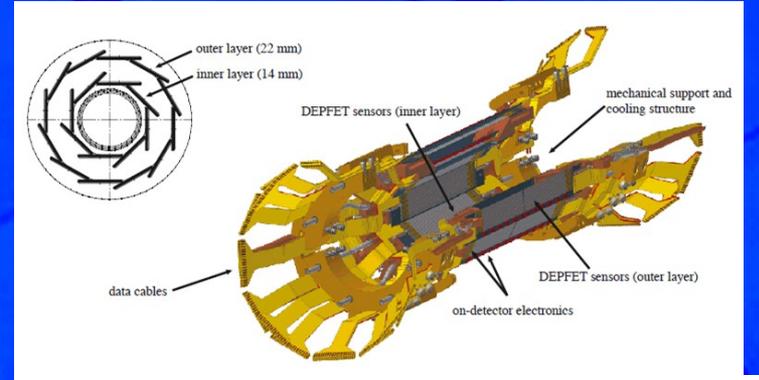
Si Thickness (μm)	a (μm)	b (μm)
25	3.5	8.9
<u>50</u>	<u>3.7</u>	<u>9.6</u>
125	3.8	11.7
300	4.0	17.5



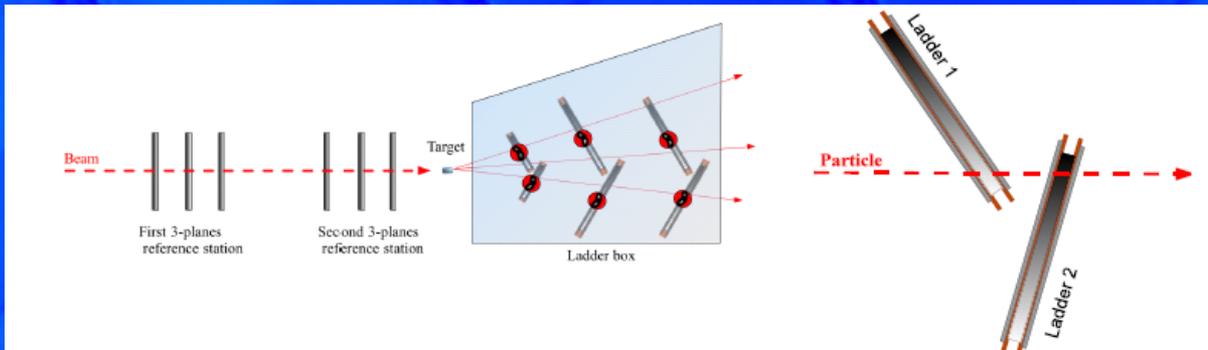
Ladder Thickness: Pioneer Experiments



STAR 0.37% X_0



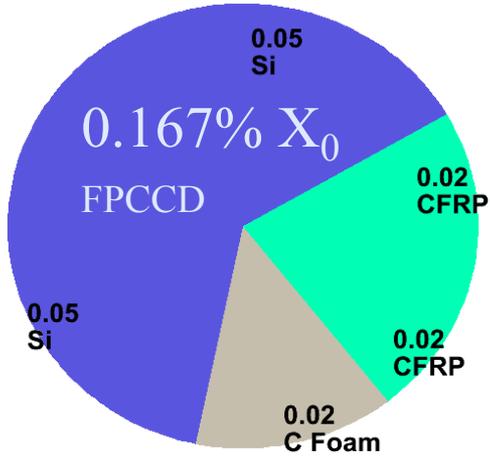
Belle-II 0.19% X_0



Monolithic Pixel-based Ladder Thickness



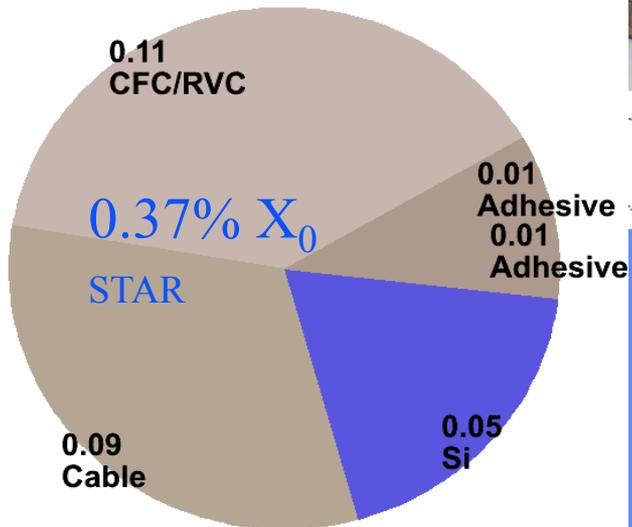
CCD



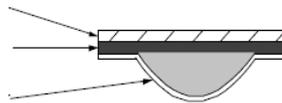
Material budget generally not dominated by sensor, all designs assume airflow cooling.



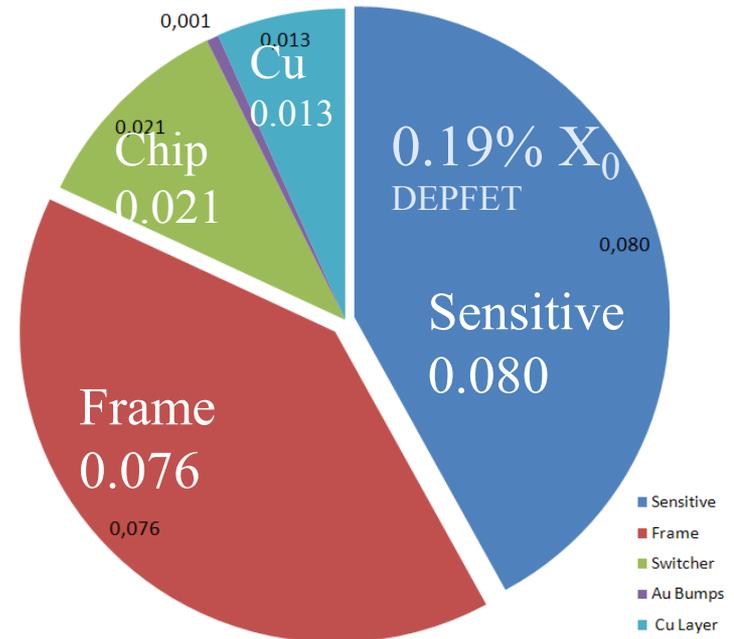
STAR HFT



Prototype with 50 μm IMOSA-5 chips



1st layer ladder: 0.19 % X_0



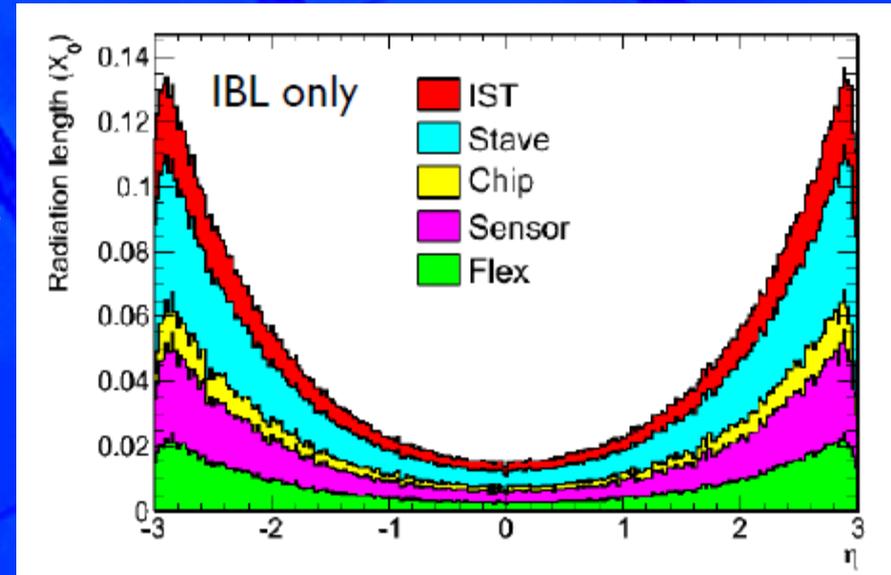
Ladder Material Budget: Experience from LHC and RHIC upgrades



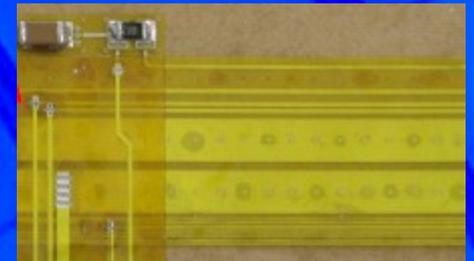
ATLAS current pixels 3.5% X_0 / layer (1.47% stave, 0.92% services)

IBL 1.5% X_0 (0.40% services)

SLHC upgrade target value $<2\%$ X_0 / layer



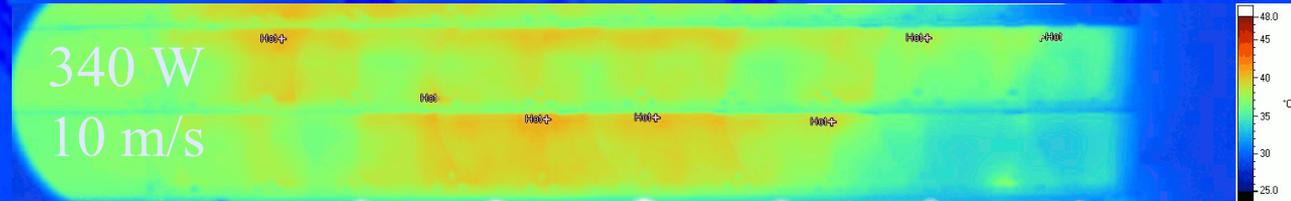
Flex cable material comparable (larger) than (thinned) sensor
STAR HFT and ATLAS IBL have flex with Al traces in active area + wire-bonds connections (STAR flex = 0.075% X_0 in active area).



Ladder Material Budget: Experience from LHC and RHIC upgrades



Tests at LBNL with STAR HFT mock-up show that airflow-based cooling can remove 170 mW/cm^2 with $\Delta T \sim 10^\circ$ above ambient with $< 10 \text{ m/s}$ and ladder vibrations within $10 \mu\text{m}$ r.m.s.



L. Greiner

Power distribution: in-chip DC-DC converter or serial power ;



SP takes less material than DC-DC converter (ATLAS estimate SP/DC-DC ~ 0.25), ATLAS demonstrated its feasibility on half stave, integration into FE chip design.

Mechanics for the Vertex Tracker : Stability requirements



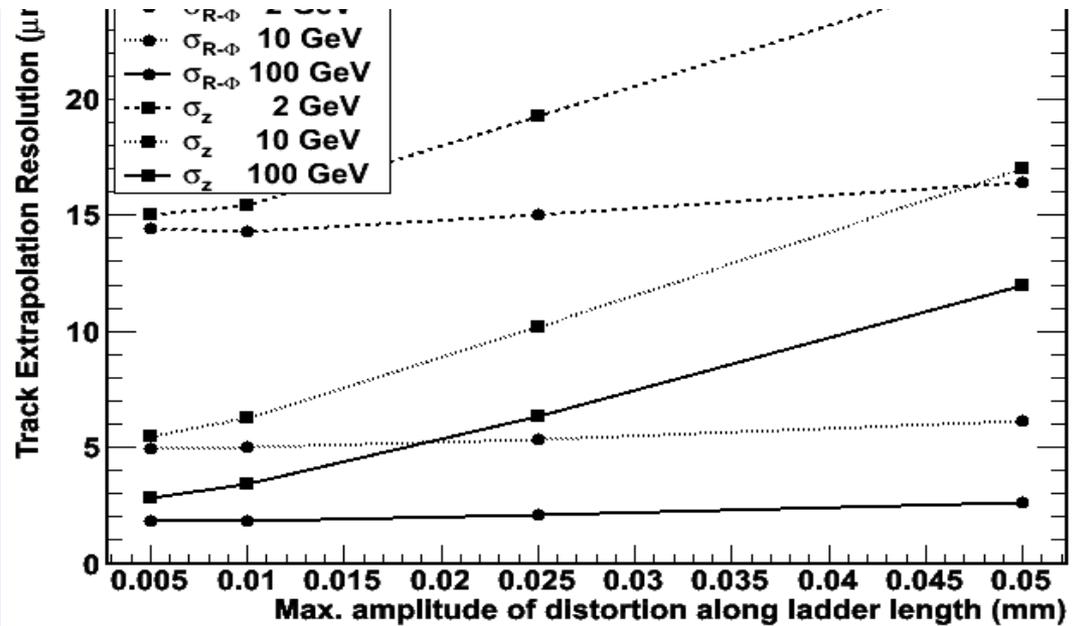
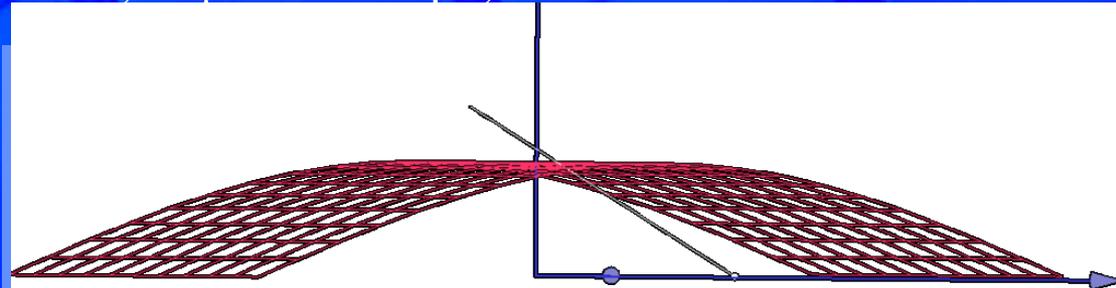
STAR stability requirement: $6\mu\text{m}$ r.m.s., $20\mu\text{m}$ envelope;

LC Vertex Tracker:

Study track extrapolation resolution in $R-\phi$ and z with amplitude of longitudinal and transverse ladder distortion;

Use new Marlin VTX digitiser under development for studies with the CLIC-ILD geometry;

Still need to propagate effect through ZVTOP b-tagging but appear that $<10-15\mu\text{m}$ envelope will be required.

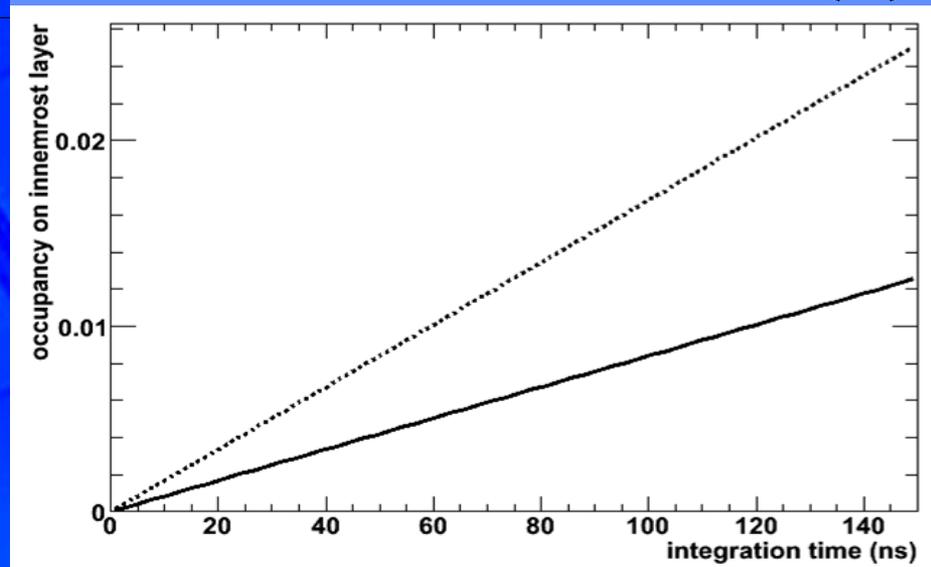
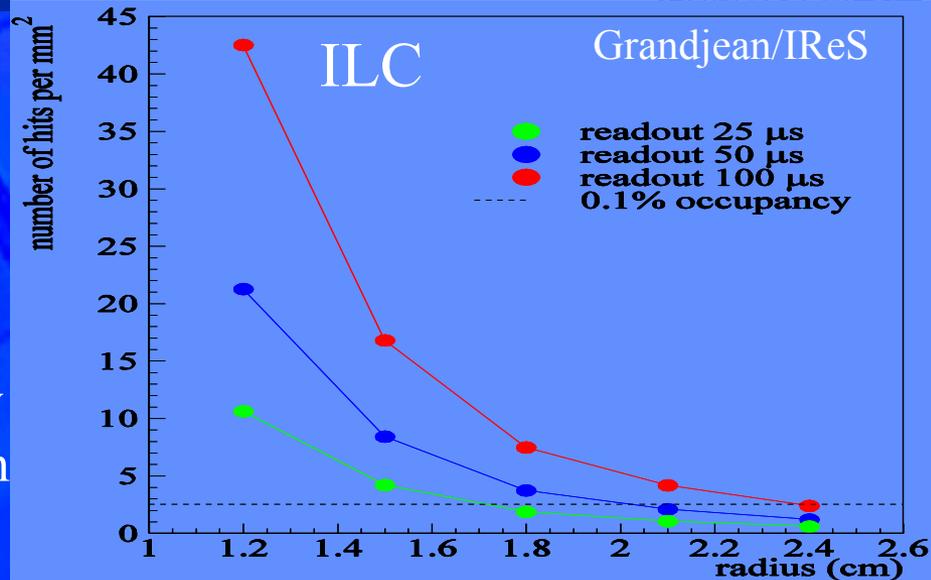
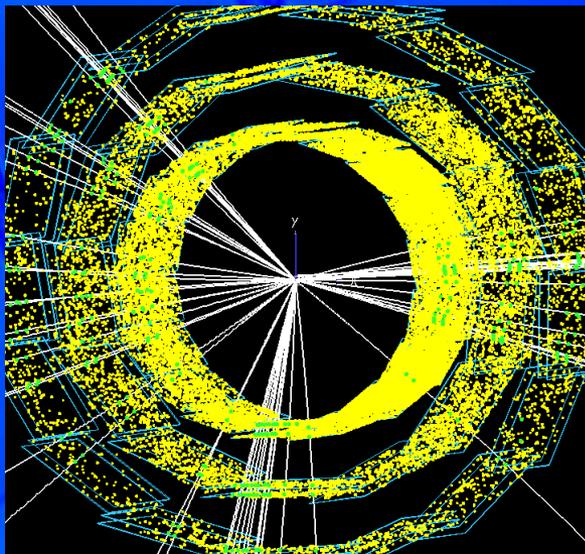


Space-Time Granularity and Occupancy



Simulation of pair backgrounds in VTX defines space-time granularity to keep local occupancy compatible with precision vertex tracking;

Requirements in terms of space granularity from occupancy and single point resolution appear to be comparable



Read-out Speed and Occupancy



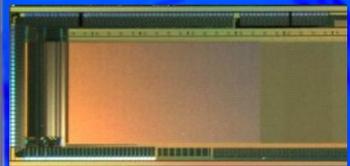
Most demanding requirement is mitigating occupancy:

ILC (2820 bunches w/ $\Delta t_{bx}=337\text{ns}$) r/o of first layers in 25-50 μs , time-stamping or $5\mu\text{m}$ pixels, at CLIC (312 bunches) $\Delta t_{bx} = 0.5\text{ns}$ possibly 15-30 ns time-stamping

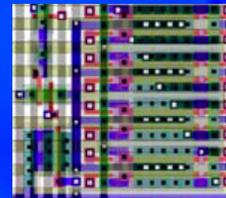
- Fast continuous readout architectures

CMOS APS

Double-sided col //
binary r/o + 0 suppress,
with $15\mu\text{m}$ pixels

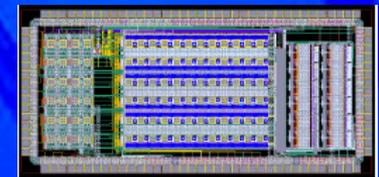


CMOS CAP Pixels



r/o 20 times during
train data store on
periphery

DEPFET Pixels

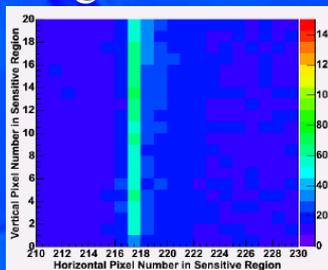


- In situ storage with high space-time granularity and r/o at end of train

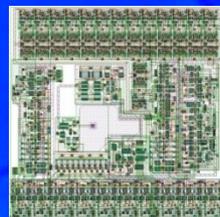
Fine Pixel CCD

$5\mu\text{m}$ pixels

Reject bkg with cluster shape

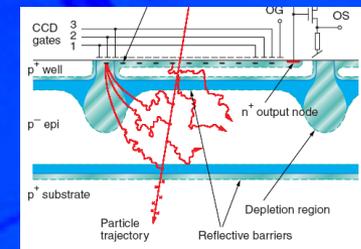


ChronoPixel

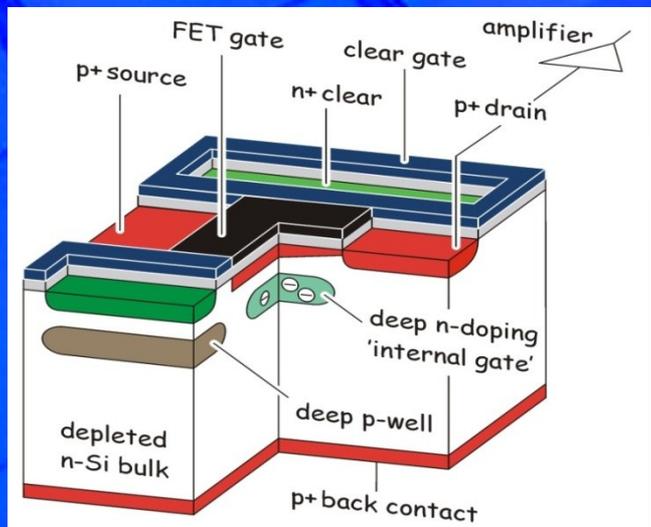
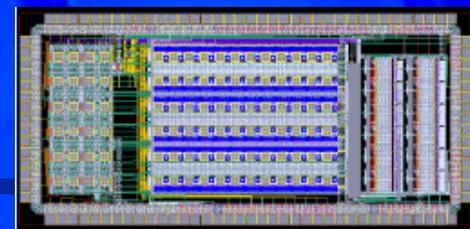


ISIS

In-situ 20-cell
charge storage

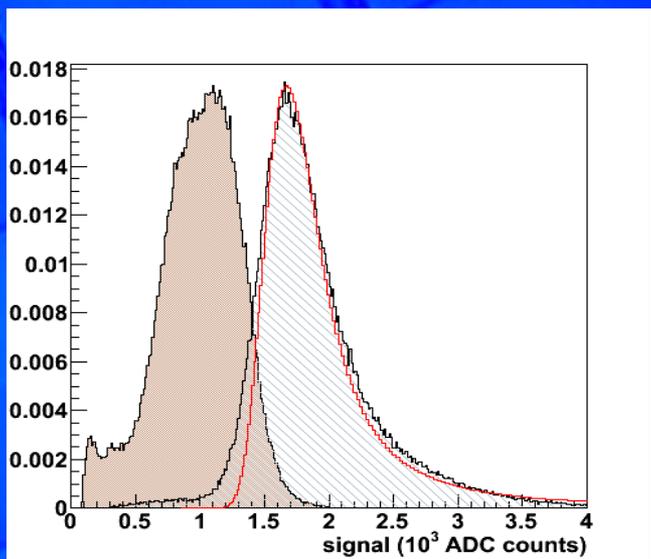


Technologies for the Vertex Tracker : DEPFET



Important experience with application
at KEKB Belle-II upgrade.

- fully depleted sensitive volume
 - fast signal rise time (\sim ns), small cluster size
- Fabrication at MPI HLL
 - Wafer scale devices possible
 - no stitching, 100% fill factor
- no charge transfer needed
 - faster read out
 - better radiation tolerance
- Charge collection in "off" state, read out on demand
 - potentially low power device
- internal amplification
 - charge-to-current conversion
 - large signal, even for thin devices
 - r/o cap. independent of sensor thickness



Technologies for the Vertex Tracker

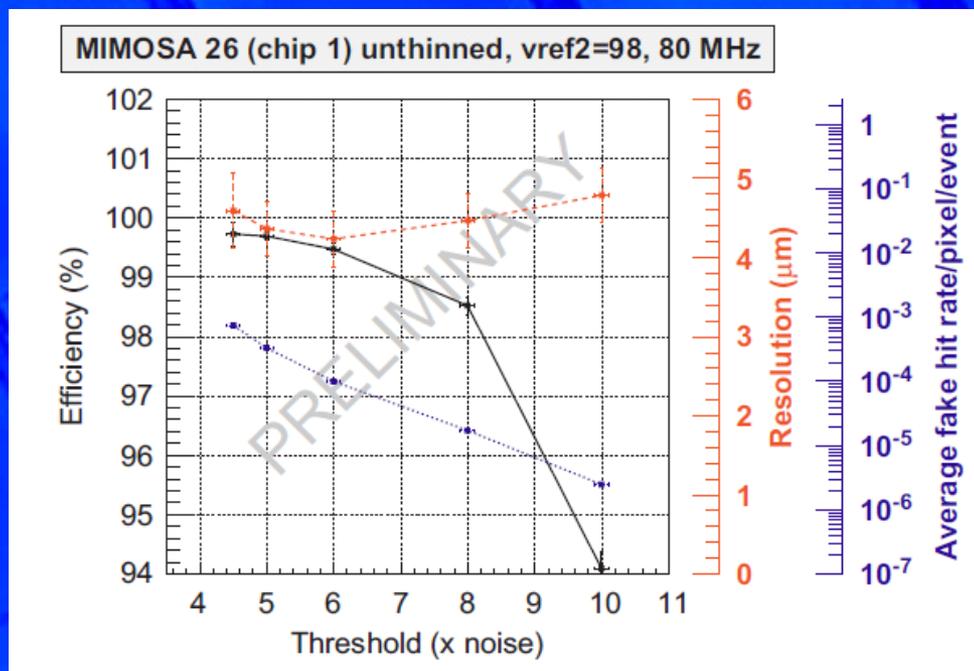
CMOS Active Pixel Sensors



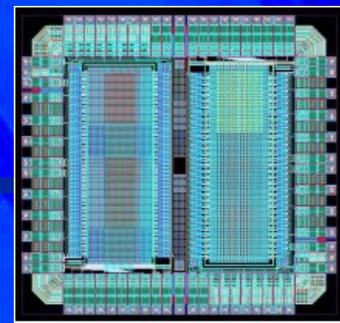
CMOS APS offers high granularity with thin sensitive layer, signal sensing and some processing in pixel, analog and/or digital processing in periphery, fast column parallel readout (rolling shutter);

R&D driven by ILC in the last decade, significant progress towards sensors ready for applications in real experiments (STAR, CBM)

S/N, speed and radiation tolerance motivate transition towards CMOS technology integrated with high resistivity sensitive layer.



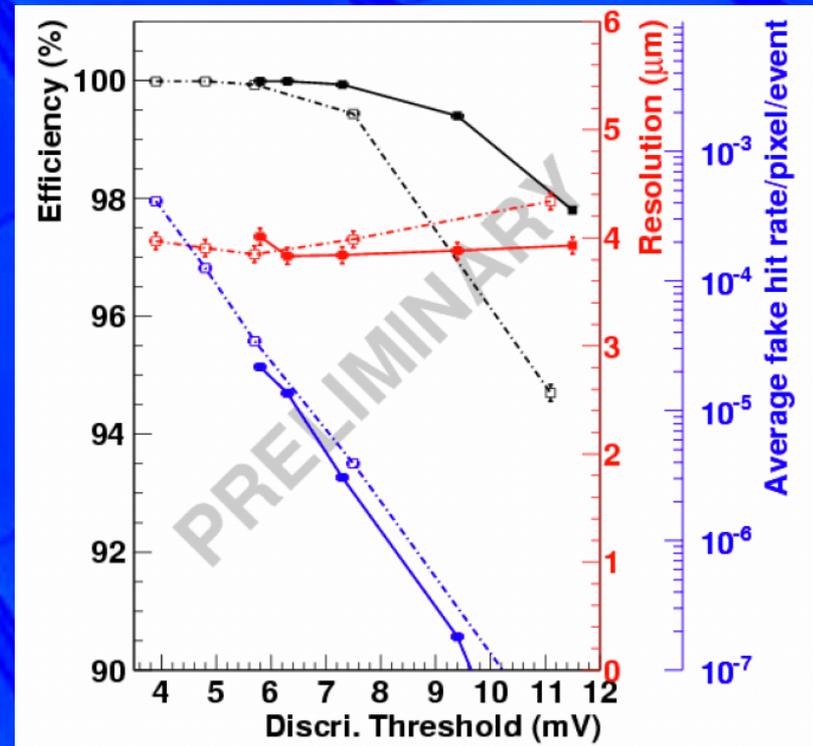
Technologies for the Vertex Tracker CMOS w/ High-Res. Substrate



Port of std CMOS process on wafers with high resistivity substrate offer higher charge yield, faster charge collection dominated by drift, improved radiation tolerance and faster r/o:

IPHC Mimosa 26 in 0.35AMS-OPTO with 400 Ω -cm epi layer, binary readout 80-115MHz (115-85 μ s integration time) M26 tested at SPS in EUDET telescope (10 and 15 μ m high-res epi layer):

MIMOSA sensors with high-res epi-layer intended for application in STAR HFT (IReS, LBNL);

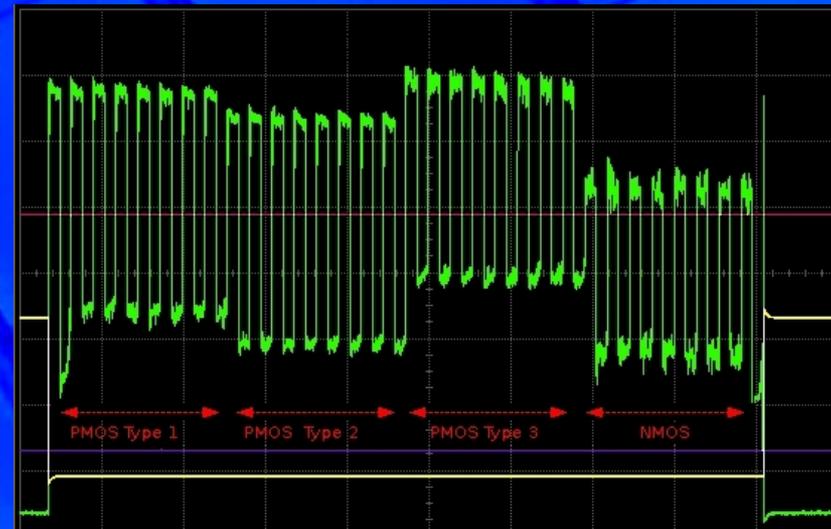
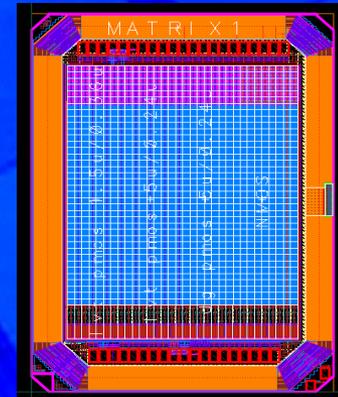
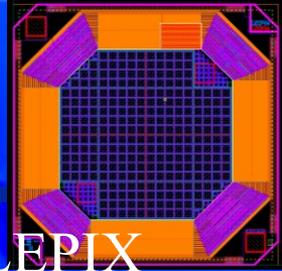


Technologies for the Vertex Tracker CMOS w/ High-Res. Substrate

Port 90 nm CMOS process to high-res wafers developed by the LEPIX collaboration (CERN, INFN, IPHC, UCSC, Kosice, ...) led by CERN:
expect good radiation hardness (charge collection by drift),
parallel pixel signal processing with 25ns time tagging,
low power consumption with low capacitance, ...

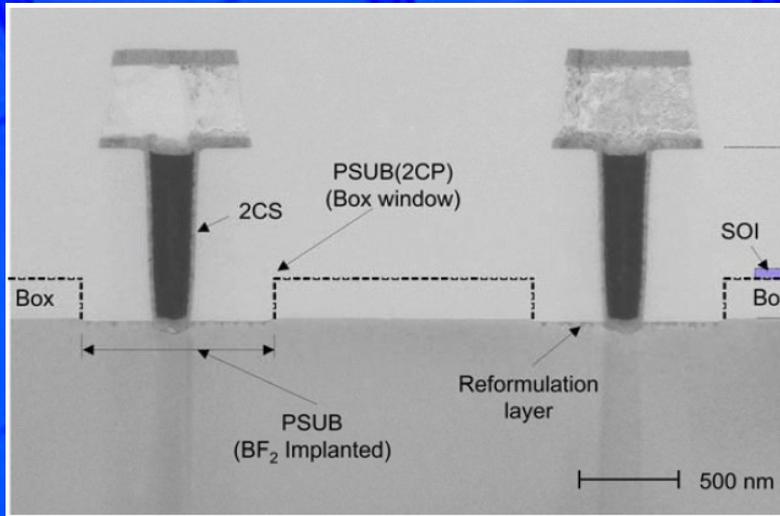
First structures produced and being tested at CERN:

- breakdown voltage > 30 V on std Si,
- expect to get depletion ~ 50 μm for a collection electrode capacitance of a few fF, or less.



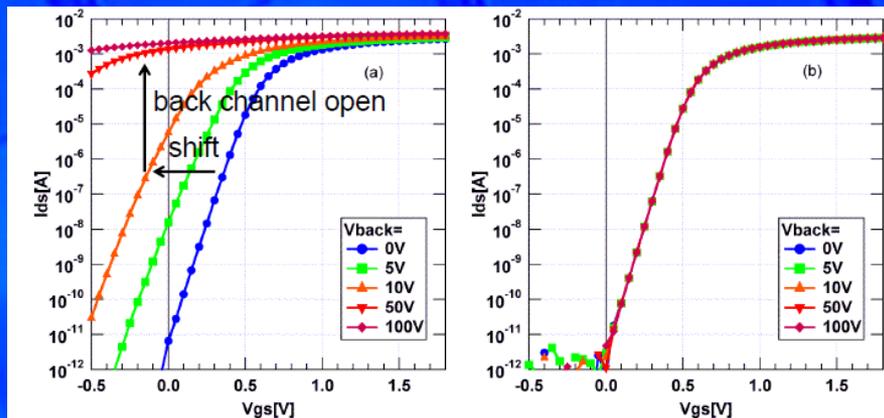
Technologies for the Vertex Tracker

CMOS w/ High-Res Substrate: Silicon-On-Insulator



SOI process offers appealing opportunity for monolithic pixel sensors, removing limitations of bulk CMOS processes;

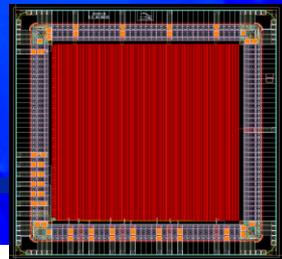
- High-res sensitive volume \rightarrow large signals;
- Deep submicron CMOS electronics;
- No interconnections;
- Low collection electrode capacitance;
- Potentially Rad-hard;
- Main challenges: transistor back-gating & charge trapping in BOX



Back-gating suppressed by adding buried p-well (KEK);

Nested well structure being tested (FNAL+KEK), double SOI layer wafer; Successful sensor back-thinning to 50 & 110 μ m (LBNL, FNAL and KEK)

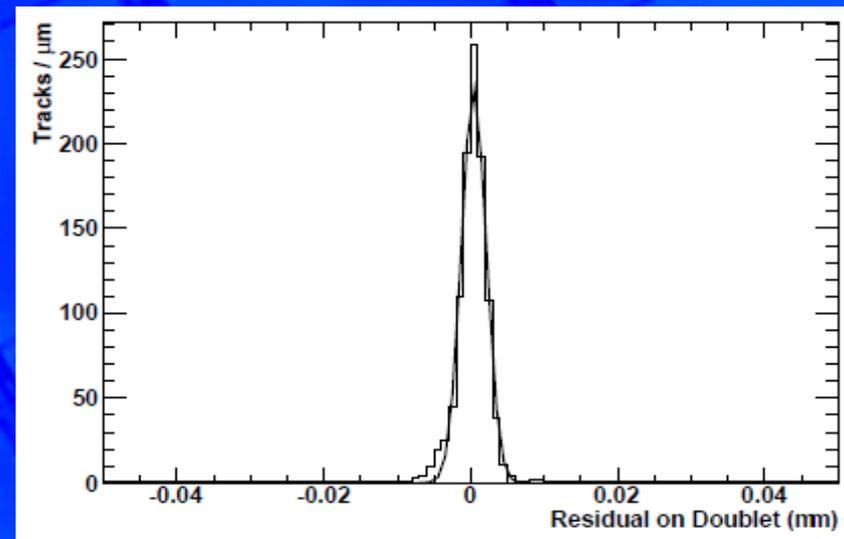
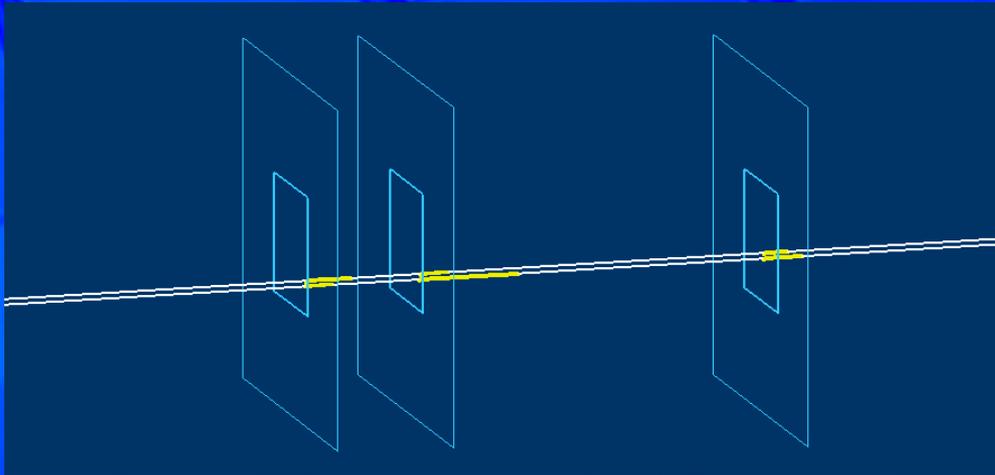
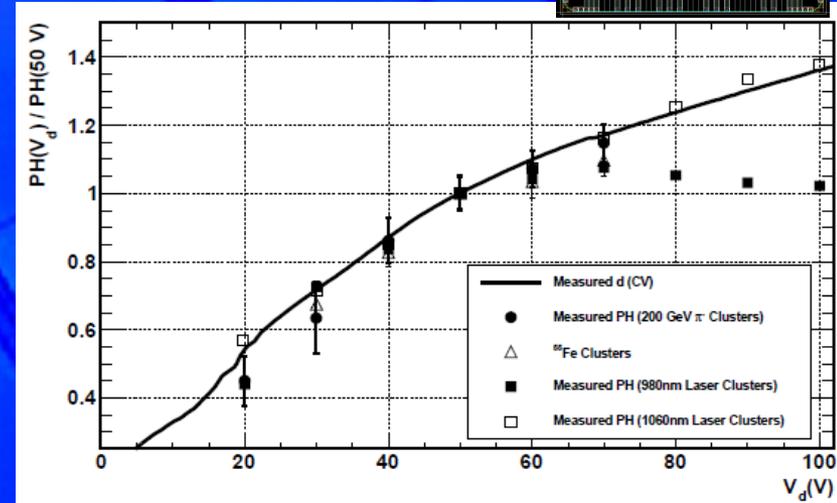
Technologies for the Vertex Tracker CMOS w/ High-Res Substrate: Silicon-On-Insulator



OKI-KEK MPW, 700 Ω -cm handle wafer:
LBNL test chip w/ analog pixels on 15 μ m
pitch and various designs

Prototypes with BPW operates up to 100V
w/ depletion depth of $\sim 150\mu\text{m}$ \rightarrow S/N > 50;
SPS beam test with 200 GeV π^- shows

$$\varepsilon = 0.99^{+0.01}_{-0.03} \text{ and } \sigma_{\text{point}} = (1.12 \pm 0.03) \mu\text{m}$$



Technologies for the Vertex Tracker

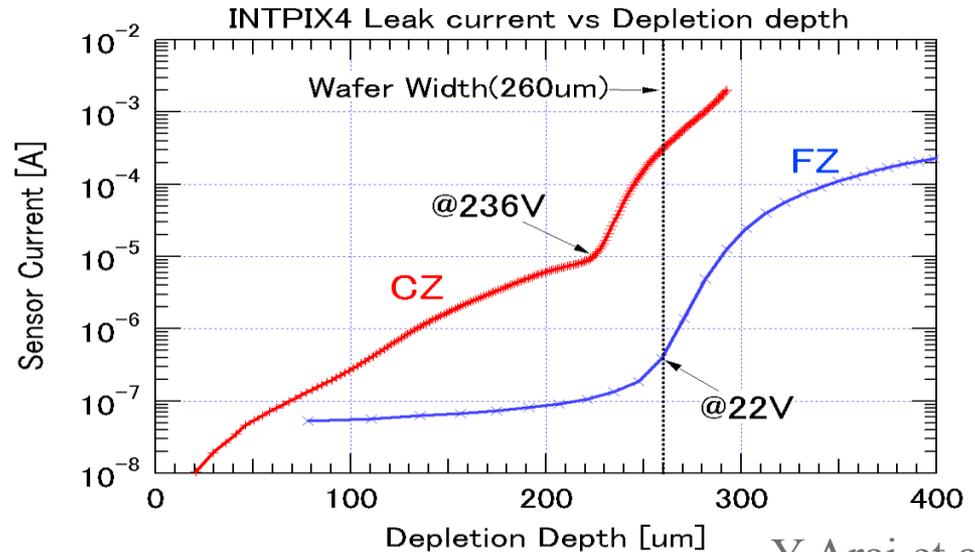
CMOS w/ High-Res Substrate: Silicon-On-Insulator



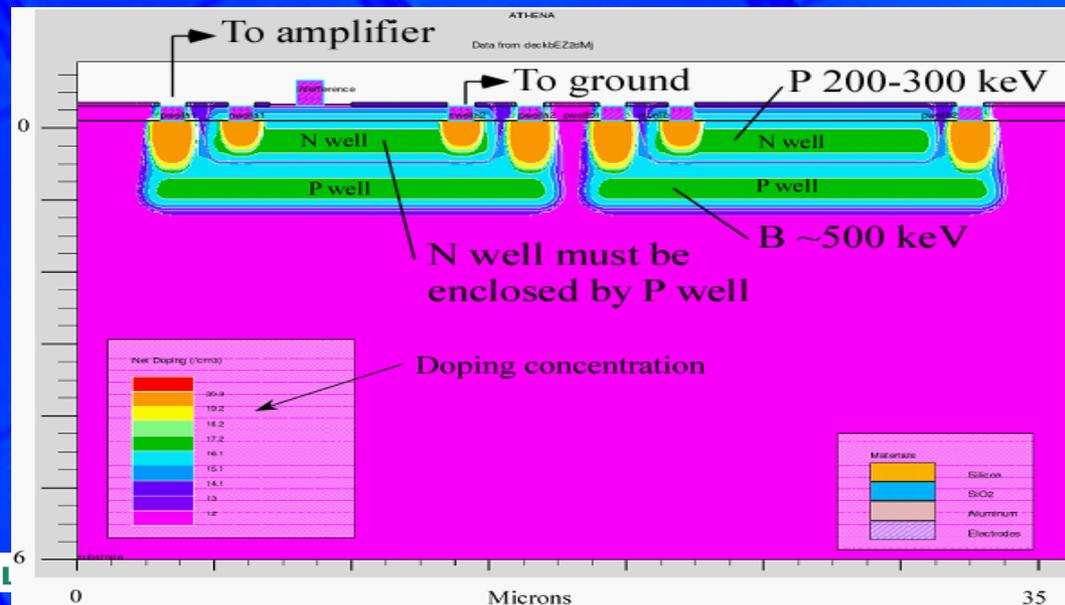
SOI with Float Zone Si gives encouraging results at KEK and FNAL, full depletion of 260 μm thickness with 22 V (but higher leakage);

FNAL MAMBO chip exploring nested well design: deep p-well to collect charge and shallow n-well to shield electronics;

Complex architecture with large pixel size, will need to be revisited for LC application.



Y Arai et al.



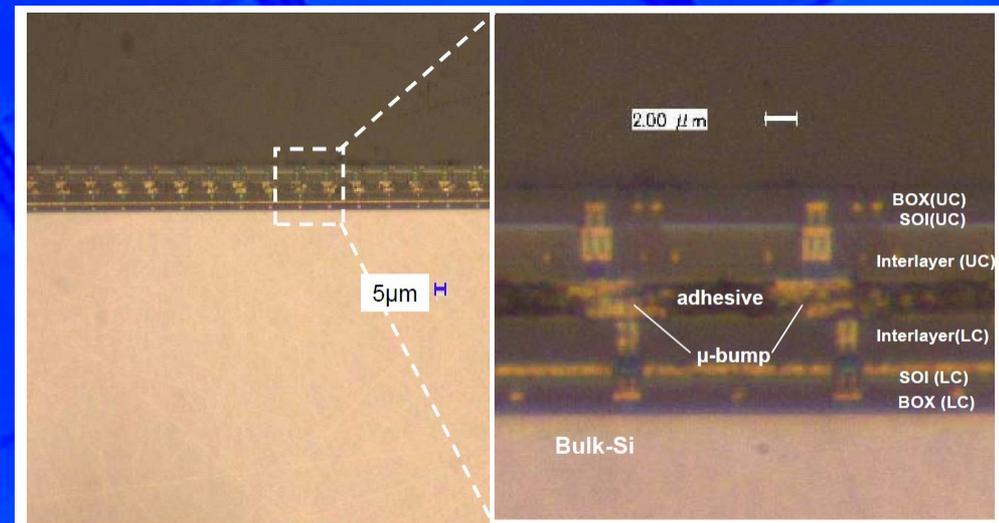
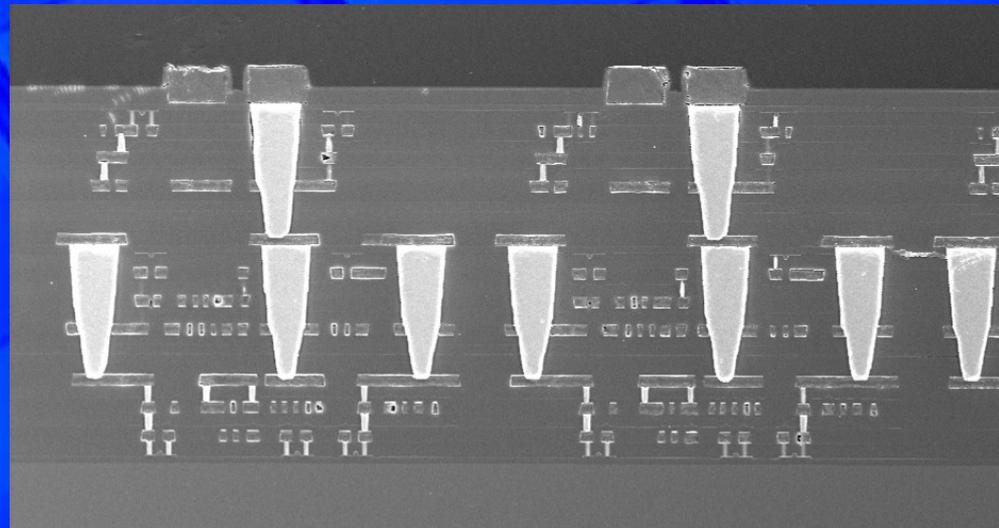
Technologies for the Vertex Tracker

3D Vertical integration



FNAL leading collaboration for sensor application of 3D technology at Chartered/Tezzaron

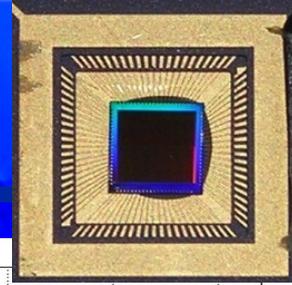
3D CMOS offers several advantages:
-heterogeneous tiers
-Isolation of electronics from sensor
- industrial standard
but progress very slow so far;



Test of 3D-SOI at T-Micro
(KEK,LBNL, FNAL)

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Architectures for the Vertex Tracker : Time stamping



Chronopixel develop architecture w/ in-pixel time stamping, digital readout during inter-train period;

Current prototype in TSMC 180nm [45] CMOS, low-res $7\mu\text{m}$ [15] epi and no deep p-well: first test of architecture with $50\mu\text{m}$ pitch [10];

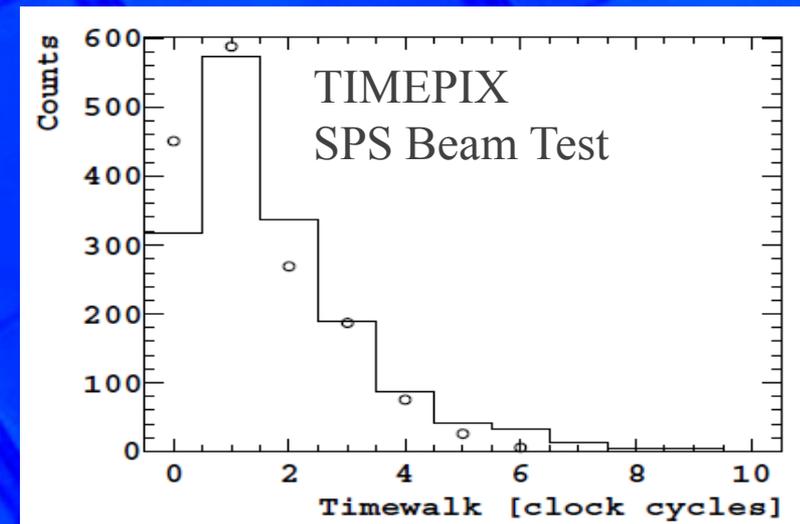
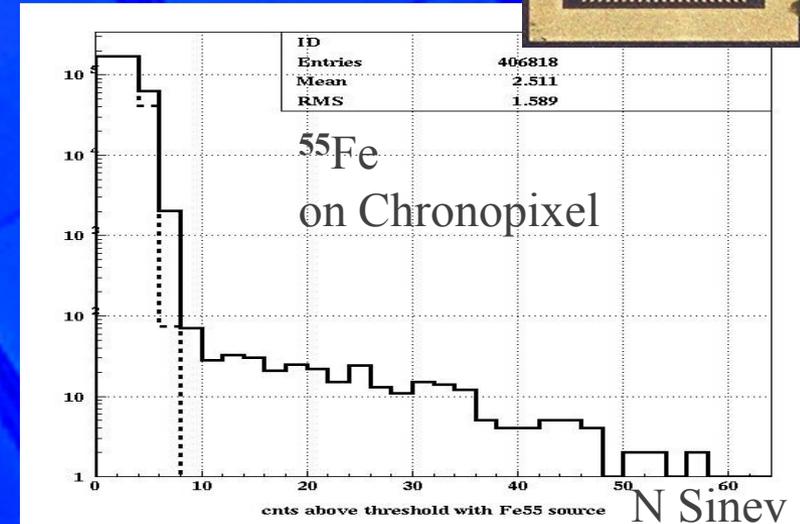
Pixel noise $25e^-$ [24] using soft reset+feedback, Pixel capacitance $\sim 3.5\text{fF}$, gain $35.7\mu\text{V}/e^-$ [10]

Comparator threshold spread 24.6mV [9];

Power dissipation $125\text{mW}/\text{cm}^2$ [15]; Time stamping at 7.27MHz \rightarrow 140ns resolution;

Faster time stamping (CLIC $\Delta t=0.5\text{ns}$) limited by charge collection time. [] ILC requirement

VELOPIX readout chip developed from TIMEPIX for LHCb upgrade may offer interesting approach to fast-time stamping.





Physics requirements at a future linear collider motivated significant R&D on monolithic pixel sensors to achieve small pixel cells with integrated charge sensing and some data processing, thin sensors with low power consumption and fast readout and/or high space-time granularity;

Contemplating energy increase from 0.5 TeV to multi-TeV implies new requirements on fast time stamping, which need to be addressed by dedicated R&D;

Technologies developed in ILC-motivated R&D have significant impact on other particle physics experiments as well as imaging and spectroscopy in other fields of science from electron microscopy to biology and astronomy.